Application/Control No. Applicant(s)/Patent Under 16/627 567 Reexamination Stoschek et al. Notice of References Cited Art Unit Examiner JEAN PAUL CASS 3668 Page 1 of 1 **U.S. PATENT DOCUMENTS Document Number** Date Name **CPC Classification US Classification** MM-YYYY Country Code-Number-Kind Code 02-2015 US-20150035437-A1 Panopoulos: Peter J. F21S8/085 315/291 * US-9383753-B1 07-2016 Templeton; Bradley G01S17/42 1/1 Wood; Derek С US-6804607-B1 10-2004 G05D1/1062 340/425.5 03-2018 D US-20180075762-A1 Gadgil; Anup A. G01C23/00 1/1 Ε US-20030043058-A1 03-2003 Jamieson, James R. G01S17/58 340/961 * F US-RE46672-E 01-2018 Hall; David S. G01S7/4811 1/1 * G 12-2009 356/5.1 US-7639347-B2 Eaton; Robert B. G01S7/4818 * 05-2022 Н US-11346925-B2 Russell; Austin K. G01S7/4868 1/1 * US-20220043127-A1 02-2022 LaChapelle; Joseph G. G01S7/484 1/1 J US-20210356601-A1 11-2021 Burbank; Istvan Peter G01S17/931 1/1 * Κ US-20220120905-A1 04-2022 Wachter; Luke G01S7/486 1/1 L US-20220107396-A1 04-2022 Hughes; Sean P. G01S7/4817 1/1 Μ **FOREIGN PATENT DOCUMENTS Document Number** Date **CPC Classification** Country Name MM-YYYY Country Code-Number-Kind Code Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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